

Title (en)  
X-RAY DIAGNOSTIC INSTALLATION WITH AN X-RAY TUBE

Publication  
**EP 0150364 B1 19880406 (DE)**

Application  
**EP 84115065 A 19841210**

Priority  
DE 3401749 A 19840119

Abstract (en)  
[origin: US4748650A] In an exemplary embodiment a fine electron beam is generated which impinges on an elemental part of an anode focus region. A beam deflection system is controlled by a control circuit such that the point of impingement of the electron beam on the anode focus region moves along a predetermined path whose configuration effectively determines the desired focus size and shape.

IPC 1-7  
**H01J 35/14**; **H01J 35/30**

IPC 8 full level  
**H01J 35/14** (2006.01); **H01J 35/30** (2006.01); **H05G 1/52** (2006.01)

CPC (source: EP US)  
**H01J 35/045** (2013.01 - EP US); **H01J 35/147** (2019.04 - EP US); **H01J 35/30** (2013.01 - EP US)

Cited by  
DE19832972A1; DE4124294A1; DE4143490C2; EP0715333A1; EP1087419A3; US5857008A; EP0389326A1; FR2644931A1; US5125019A; US6236713B1; WO0025342A1; WO9629723A1

Designated contracting state (EPC)  
CH DE FR LI

DOCDB simple family (publication)  
**EP 0150364 A2 19850807**; **EP 0150364 A3 19850904**; **EP 0150364 B1 19880406**; DE 3401749 A1 19850801; DE 3470361 D1 19880511; JP S60132000 U 19850903; US 4748650 A 19880531

DOCDB simple family (application)  
**EP 84115065 A 19841210**; DE 3401749 A 19840119; DE 3470361 T 19841210; JP 405385 U 19850116; US 94842386 A 19861230